## **ELECTRONIC INFORMATION DISCLOSURE STATEMENT**

Electronic Version v18

Stylesheet Version v18.0

Title of Invention

METHOD AND STRUCTURE FOR IMPROVING CMOS DEVICE RELIABILITY USING COMBINATIONS OF INSULATING MATERIALS

Application Number :

Confirmation Number:

First Named Applicant: Haining Yang
Attorney Docket Number: FIS920040194US1

Art Unit: Examiner:

Search string: (5851893 or 6724053).pn

## **US Patent Documents**

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	5851893	1998-12-22	Gardner et al.			
	2	6724053	2004-04-20	Divakaruni et al			

## **Signature**

Examiner Name	Date		